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Influence of elastic and inelastic scattering on energy spectra of electrons emitted from solids

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382	Multiple Scattering of Low-Energy Electrons in Aluminum. 1983 , 30, 4409-4412		5
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379	A sequential method for removing the inelastic loss contribution from Auger electron spectroscopic data. 1983 , 17, 53-69		45
378	Concentration depth profiles by XPS; A new approach. <i>Surface Science</i> , 1983 , 129, 355-365	1.8	74
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